



IFCW

PATENT
8053-1016

IN THE U.S. PATENT AND TRADEMARK OFFICE

In re application of:

Kazuhiro NAKAJIMA et al.

Conf.: 9942

Appl. No.: 10/625,695

Group: 2811

Filed: July 24, 2003

Examiner: Ori Nadav

For: PRODUCTION PROCESS FOR PRODUCING
SEMICONDUCTOR DEVICES, SEMICONDUCTOR DEVICES
PRODUCED THEREBY, AND TEST SYSTEM FOR
CARRYING OUT YIELD-RATE TEST IN
PRODUCTION OF SUCH SEMICONDUCTOR DEVICES

AMENDMENT

Assistant Commissioner for Patents
P.O. Box 1450
Alexandria, VA 22313-1450
Sir:

October 19, 2004

In response to the Office Action mailed September 23, 2004, please amend the above-identified application as follows:

Amendments to the Claims are reflected in the listing of claims which begins on page 2 of this paper.

Remarks begin on page 5 of this paper.